

Search Notes



Application/Control No.

10/780,930

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
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